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INFORMATION DISCLOSURE STATEMENT
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Applicant: YAMADA et al

Appln. No.: 09/993,967

Filing Date: November 27, 2001

Examiner: to be assigned Group Art Unit: 2812

U.S. PATENT DOCUMENTS

Examiner's Initials*	Document Number	Date MM/YYYY	Name (Family Name of First Inventor)	Class	Sub Class	Filing Date (if appropriate)
ML	AR 5,929,476	07/1999	PRALL			
	BR					
	CR					
	DR					
	ER					
	FR					
	GR					
	HR					
	IR					

FOREIGN PATENT DOCUMENTS

	Document Number	Date MM/YYYY	Country	Inventor Name	English Abstract		Translation Readily Available	
					Enclosed	No	Enclose	No
JR								
KR								
LR								
MR								
NR								
OR								
PR								
QR								
RR								
SR								

OTHER (Including in this order Author, Title, Periodical Name, Date, Pertinent Pages, etc.)

ML	TR	Patent Abstracts of Japan, Publ. No. JP 01 158768, Vol. 013, No. 429, 1989	
ML	UR	Patent Abstracts of Japan, Publ. No. JP 01 147860, Vol. 013, No. 407, 1989	
ML	VR	Rupp et al., "Extending trench DRAM technology to 0.15 µm groundrule and beyond", IEDM Technical Digest, 1999, pg. 33-36	
ML	WR	Gruening et al., "A novel trench DRAM cell with a <u>VERtical</u> access transistor and <u>BuriEd STrap</u> (VERI BEST) for 4Gb/16Gb", IEDM Technical Digest, 1999, pg. 25-28	
ML	XR	"High density vertical DRAM cell", IBM Technical Disclosure Bulletin, Vol. 29, No. 5, 1986, pg. 2335-2340	
	YR		

Examiner

Date Considered:

*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.